

2018 TTTC tutorials during ITC Test Week – This is a quick overview. More details will be available later in August.

Sunday, 10/28					
Morning			Afternoon		
1	Learning Techniques for Reliability Monitoring, Mitigation and Adaptation	Mehdi Tahoori (Karlsruhe Institute of Technology)	4	Machine Learning for Test and Test for Machine Learning – A Journey to AI	Li-C. Wang (UCSB)
2	Integrated Bulk Sensors enabling On-line test for Radiation Induced Soft-Errors and Noise Sensing	Frank Sill Torres (Federal University of Minas Gerais), Rodrigo Possamai Bastos (TIMA Laboratory, Université Grenoble Alpes)	5	Mixed-signal DfT & BIST: Trends, Principles, and Solutions	Stephen Sunter (Mentor, a Siemens Business )
3	Targeting "Zero Defect" IC Quality: Advanced Cell Aware Fault Models and Adaptive Test Automotive Reliability & Test Strategies	Adit D. Singh (Auburn University)	6	Beyond DFT: The Convergence of DFM, Variability, Yield, Test, Diagnosis and Reliability	Srikanth Venkataraman (Intel Corporation), Robert Aitken (ARM)

Monday, 10/29					
Morning			Afternoon		
7	Memory Test and Repair in FinFET Era	Yervant Zorian (Synopsys)	10	Automotive Reliability & Test Strategies	Riccardo Mariani (Intel), Yervant Zorian (Synopsys)
8	From Data to Actions: Applications of Data Analytics in Semiconductor Manufacturing & Test	Haralampos-G. Stratigopoulos (Sorbonne Universités, UPMC Paris 6, CNRS, LIP6), Yiorgos Makris (The University of Texas at Dallas)	11	Testing of TSV-Based 2.5D- and 3D-Stacked ICs	Erik Jan Marinissen (IMEC), Krishnendu Chakrabarty (Duke University – Dept. ECE)
9	High-Speed I/O Testing in High-Volume Manufacturing	Salem Abdennadher (Intel Corporation), Saghir A Shaikh (Broadcom Corporation)	12	From Test to Post-Silicon Validation: Concepts and Recent Trends	Arani Sinha (Intel Corporation), Sandip Ray (NXP Semiconductors Inc.)

Updated 8/5/18